

Notice of References Cited	Application/Control No. 10/585,750		Applicant(s)/Patent Under Reexamination NOGUCHI ET AL.	
	Examiner Pablo N. Tran		Art Unit 2618	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,296,692	03-1994	Shino, Katsuhide	235/486
*	B	US-5,499,162	03-1996	Bartuska et al.	361/737
*	C	US-5,563,400	10-1996	Le Roux, Jean-Yves	235/486
*	D	US-5,752,857	05-1998	Knights, Anthony John	439/638
*	E	US-6,189,055	02-2001	Eisele et al.	710/62
*	F	US-6,332,578	12-2001	Niwata et al.	235/486
*	G	US-6,438,638	08-2002	Jones et al.	710/301
*	H	US-6,725,291	04-2004	Lai et al.	710/16
*	I	US-6,801,787	10-2004	Page et al.	455/556.1
*	J	US-7,295,443	11-2007	Mambakkam et al.	361/737
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.